EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2105	382/144-150.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/18 09:11
L2	3575	382/141-150.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/18 09:11
L3	18	382/141-150.ccls. and (threshold near2 region) with defect	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/18 09:28
L4	17	382/141-150.ccls. and (threshold) with defect with upper with lower	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/18 09:40
L5	2	("20040150813").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/05/18 10:54
L6	260	automatic adj defect adj classification	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/18 10:55
L7	84	automatic adj defect adj classification and monitor	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/18 11:09

EAST Search History

L8	22268	illuminating adj light	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/18 11:09
L9	264	illuminating adj light with ultra$violet	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/18 11:09

Home | Login | Logout | Access Information | Alerts | Sitemap | Help

IEEE Xplore ® RELEASE 2.3

Welcome United States Patent and Trademark Office

BROWSE   SEARCH   IEEE XPLORE GUIDE   SUPPORT

☑ e-mail   🖳 printer friendly

» **Search Options**

Search Results

Results for "((((inspection <near> wafer<in>metadata))<and>(threshold*<in>metadata))"
Your search matched **13 of 322** documents.
A maximum of **100** results are displayed, **25** to a page, sorted by **Relevance** in **Descending** order.

View Session History

New Search

» **Key**

IEEE JNL   IEEE Journal or Magazine

IET JNL   IET Journal or Magazine

IEEE CNF   IEEE Conference Proceeding

IET CNF   IET Conference Proceeding

IEEE STD   IEEE Standard

Modify Search

(((inspection <near> wafer<in>metadata))<and>(threshold*<in>metadata))   [Search ▷]

☐ Check to search only within this results set

Display Format: ⦿ Citation   ○ Citation & Abstract

[view selected items]   **Select All**   **Deselect All**

☐ 1. **CASTAM: A process variation analysis simulator for MOS LSI's**
Aoki, Y.; Toyabe, T.; Asai, S.; Hagiwara, T.;
Electron Devices, IEEE Transactions on
Volume 31, Issue 10, Oct 1984 Page(s):1462 - 1467
AbstractPlus | Full Text: PDF(672 KB)   IEEE JNL
Rights and Permissions

☐ 2. **Robustness evaluation of cost-optimum sampling plan for in-line wafer inspection by using Taguchi methods**
Suzuki, R.; Nakamae, K.; Fujioka, H.;
Semiconductor Manufacturing, 2005. ISSM 2005. IEEE International Symposium on
13-15 Sept. 2005 Page(s):386 - 389
Digital Object Identifier 10.1109/ISSM.2005.1513385
AbstractPlus | Full Text: PDF(322 KB)   IEEE CNF
Rights and Permissions

☐ 3. **Monitoring and preventing arc-induced wafer damage in 300mm manufacturing**
Parker, J.; Reath, M.; Krauss, A.F.; Campbell, W.J.;
Integrated Circuit Design and Technology, 2004. ICICDT '04. International Conference on
2004 Page(s):131 - 134
Digital Object Identifier 10.1109/ICICDT.2004.1309927
AbstractPlus | Full Text: PDF(441 KB)   IEEE CNF

PALM INTRANET

Content Information for 10/749670

Search Another: Application# [ ] Search   or Patent# [ ] Search

PCT / [ ] / [ ] Search   or PG PUBS # [ ] Search

Attorney Docket # [ ] Search

Bar Code # [ ] Search

[Appln Info] Contents [Petition Info] [Atty/Agent Info] [Continuity/Reexam] [Foreign Data]

Date	Status	Code	Description
04/09/2007		DOCK	CASE DOCKETED TO EXAMINER IN GAU
03/21/2006		DOCK	CASE DOCKETED TO EXAMINER IN GAU
02/22/2006		C.ADB	CORRESPONDENCE ADDRESS CHANGE
09/21/2005		M844	INFORMATION DISCLOSURE STATEMENT (IDS) FILED
09/21/2005		WIDS	INFORMATION DISCLOSURE STATEMENT (IDS) FILED
07/15/2005		DOCK	CASE DOCKETED TO EXAMINER IN GAU
06/13/2005		C.ADB	CORRESPONDENCE ADDRESS CHANGE
03/18/2005		LET.	MISCELLANEOUS INCOMING LETTER
03/18/2005		M844	INFORMATION DISCLOSURE STATEMENT (IDS) FILED
03/18/2005		WIDS	INFORMATION DISCLOSURE STATEMENT (IDS) FILED
08/26/2004		TSSCOMP	IFW TSS PROCESSING BY TECH CENTER COMPLETE
12/30/2003		RQPR	REQUEST FOR FOREIGN PRIORITY (PRIORITY PAPERS MAY BE INCLU
08/25/2004	30	DOCK	CASE DOCKETED TO EXAMINER IN GAU
06/18/2004		TI1050	TRANSFER INQUIRY TO GAU
04/30/2004	20	WROIPE	APPLICATION RETURN FROM OIPE
04/30/2004	18	ROIPE	APPLICATION RETURN TO OIPE
04/29/2004	20	OIPE	APPLICATION DISPATCHED FROM OIPE
04/30/2004		COMP	APPLICATION IS NOW COMPLETE
02/26/2004		CLSS	CASE CLASSIFIED BY OIPE
02/26/2004		L194	CLEARED BY OIPE CSR
01/24/2004		SCAN	IFW SCAN & PACR AUTO SECURITY REVIEW
12/30/2003	19	IEXX	INITIAL EXAM TEAM NN

[Appln Info] Contents [Petition Info] [Atty/Agent Info] [Continuity/Reexam] [Foreign Data]

To go back use Back button on your browser toolbar.

Back to PALM | ASSIGNMENT | OASIS | Home page